



Shenzhen Tuofeng Semiconductor Technology Co., Ltd

**N - CHANNEL ENHANCEMENT MODE POWER MOSFET**

SGT MOS、低内阻、低结电容开关损耗小

**TF015N03MG****• General Description**

The TF015N03MG uses advanced trench technology and design to provide excellent RDS(ON) withlowgate charge. It can be used in a wide variety of applications.

**• Features**

Advance device constructure

Low  $R_{DS(ON)}$  to minimize conduction loss

Low Gate Charge for fast switching

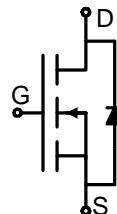
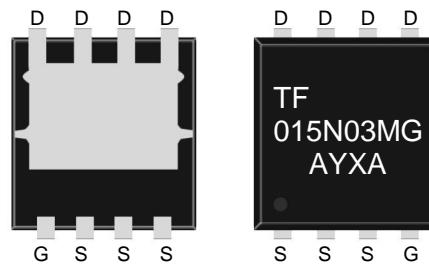
Low Thermal resistance

**• Application**

Synchronous Rectification for AC-DC/DC-DC

converter

Power Tools

**• Product Summary** $V_{DS} = 30V$   $I_D = 115A$  $R_{DS(ON)(10V\ typ)} = 1.5m\Omega$  $R_{DS(ON)(4.5V\ typ)} = 2.2m\Omega$ **PDFNWB3.3x3.3-8L****• Package Marking and Ordering Information:**

Part NO.	TF015N03MG
Marking1	015N03MG
Marking2	TF:tuofeng; AA:device code; Y:year code; X:Week
MOQ	5000

**• Absolute Maximum Ratings ( $T_C = 25^\circ C$ )**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	115	A
	$I_D @ T_C = 75^\circ C$	81	A
	$I_D @ T_C = 100^\circ C$	70	A
Pulsed Drain Current <sup>①</sup>	$I_{DM}$	450	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	40	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	1.0	W
Operating Junction Temperature	$T_J$	-55 to 150	$^\circ C$
Storage Temperature	$T_{STG}$	-55 to 150	$^\circ C$
Single Pulse Avalanche Energy	$E_{AS}$	245	mJ



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Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	3.5	° C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	57	° C/W
Soldering temperature, wavesoldering for 8 s	T <sub>sold</sub>	-	-	265	° C

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250uA	30	-	-	V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250uA	1.0	1.7	2.5	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V	-	-	1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA
Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	1.5	1.8	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 15A	-	2.2	3.0	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> = 25V, I <sub>D</sub> = 20A	-	30	-	S
Source-drain voltage	V <sub>SD</sub>	I <sub>S</sub> = 20A	-	-	1.2	V

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C <sub>iss</sub>	f = 1MHz V <sub>DS</sub> = 15V V <sub>GS</sub> = 0V	-	2517	-	pF
Output capacitance	C <sub>oss</sub>		-	1731	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	142.0	-	

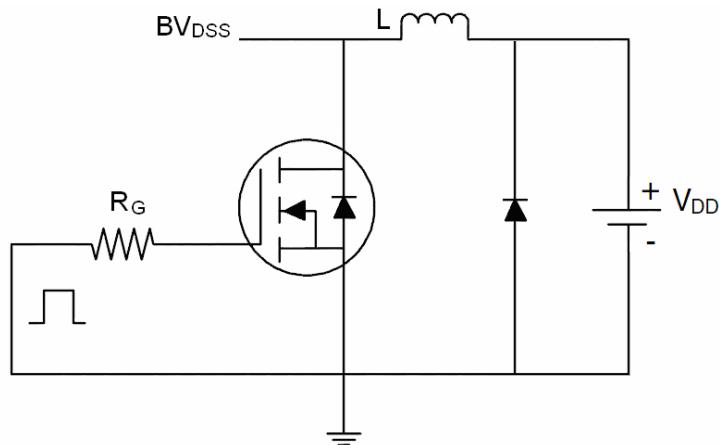
**•Gate Charge characteristics(T<sub>a</sub> = 25°C)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Gate Resistance	R <sub>g</sub>	f = 1MHz		1.3		Ω
Total gate charge	Q <sub>g</sub>	V <sub>DD</sub> = 15V I <sub>D</sub> = 20A V <sub>GS</sub> = 10V	-	39	-	nC
Gate - Source charge	Q <sub>gs</sub>		-	7.2	-	
Gate - Drain charge	Q <sub>gd</sub>		-	7.4	-	
Turn-ON Delay time	t <sub>D(on)</sub>	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 15V R <sub>G</sub> = 3.0Ω, I <sub>D</sub> = 20A		5.40		ns
Turn-ON Rise time	t <sub>r</sub>			11.0		ns
Turn-Off Delay time	t <sub>D(off)</sub>			29.0		ns
Turn-Off Fall time	t <sub>f</sub>			12.0		ns
Reverse Recovery Time	trr	V <sub>GS</sub> = 0V, I <sub>f</sub> = 20A dI/dt = 100A/μs		46.0		ns
Reverse Recovery Charge	Qrr			37.0		nC

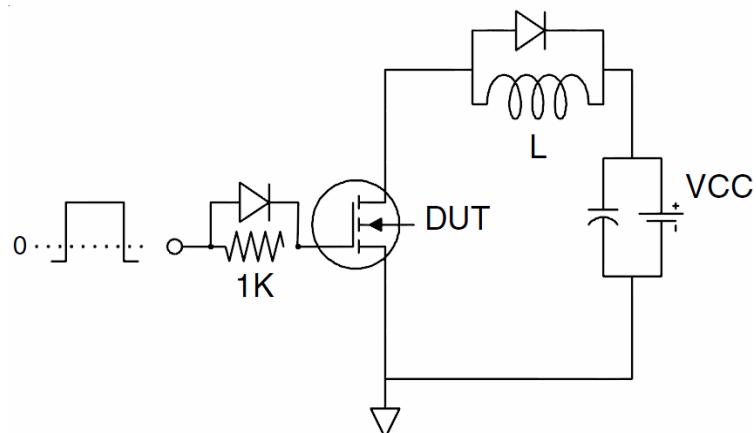
Note: ① Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% ;

### Test Circuit

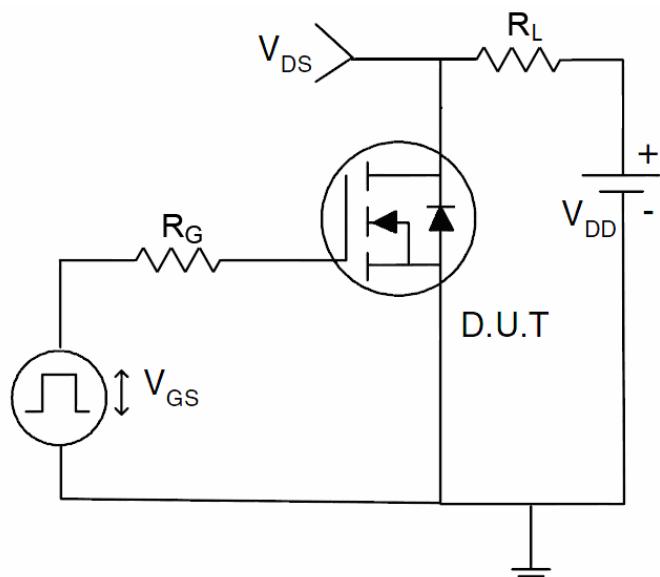
#### 1) E<sub>AS</sub> test Circuit



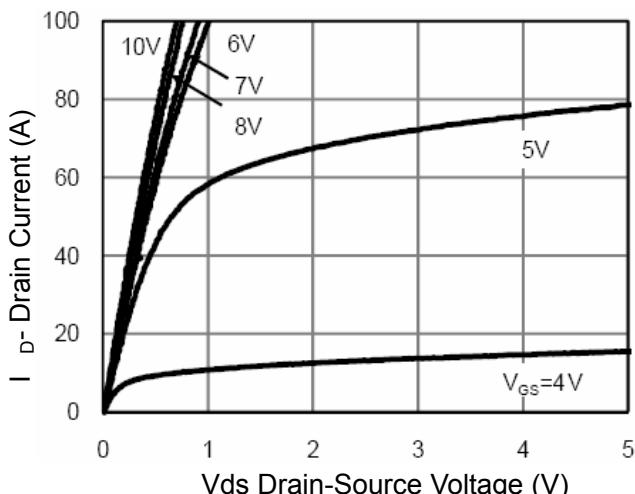
#### 2) Gate charge test Circuit



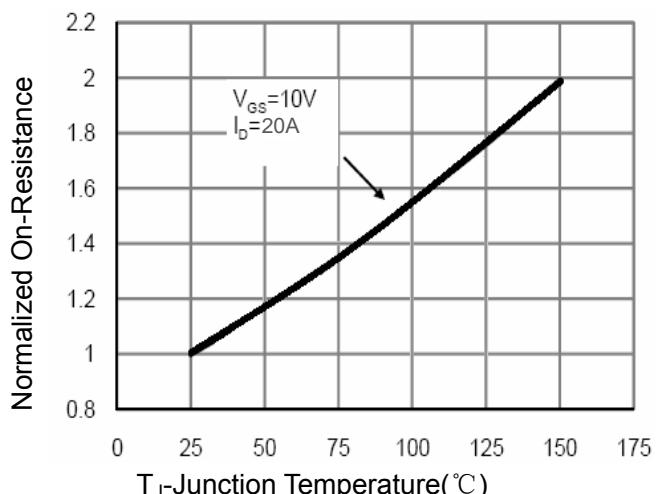
#### 3) Switch Time Test Circuit



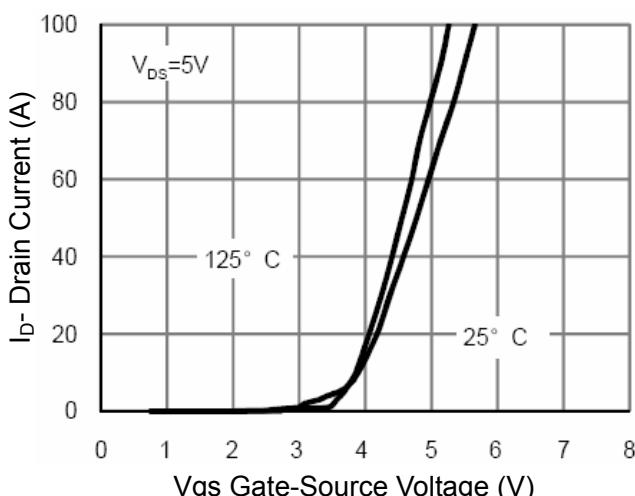
### Typical Electrical and Thermal Characteristics



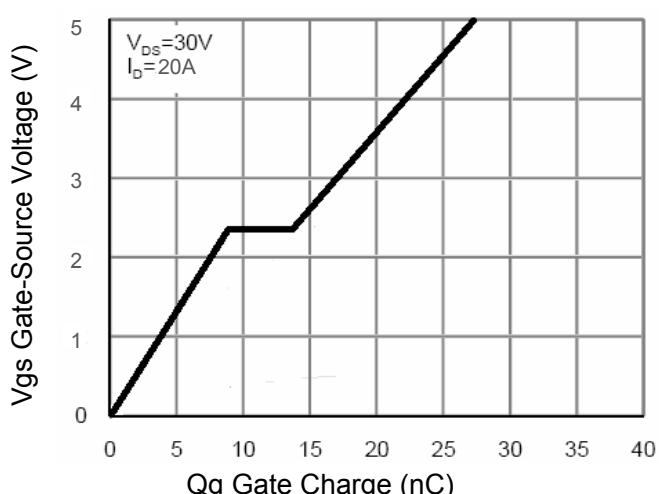
**Figure 1 Output Characteristics**



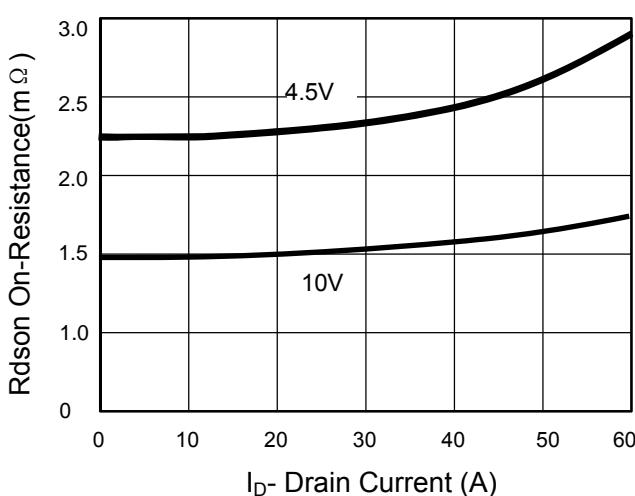
**Figure 4 Rdson-JunctionTemperature**



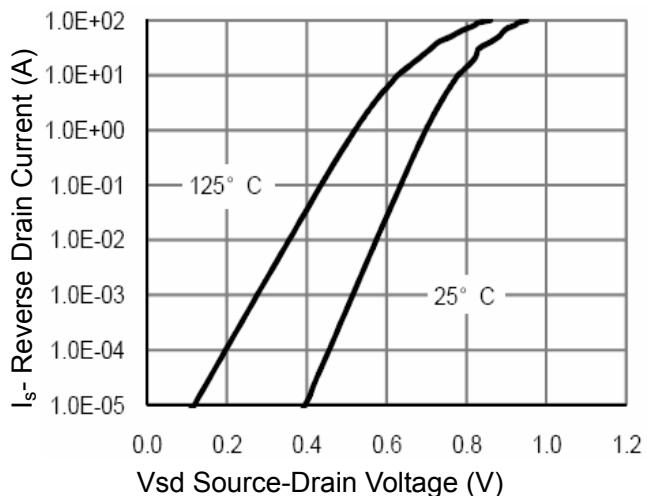
**Figure 2 Transfer Characteristics**



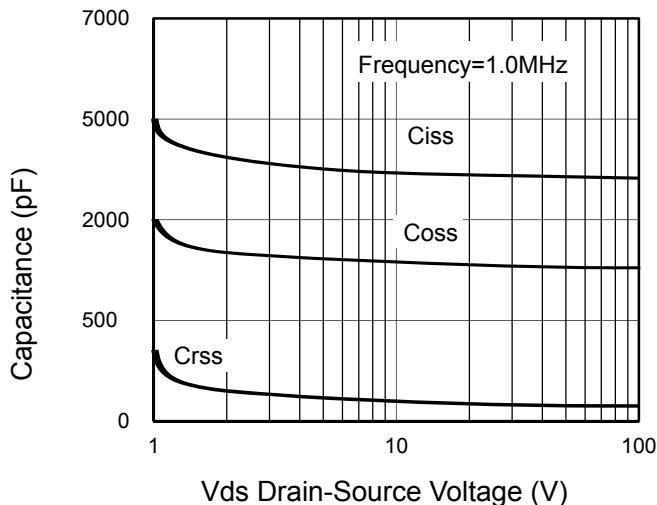
**Figure 5 Gate Charge**



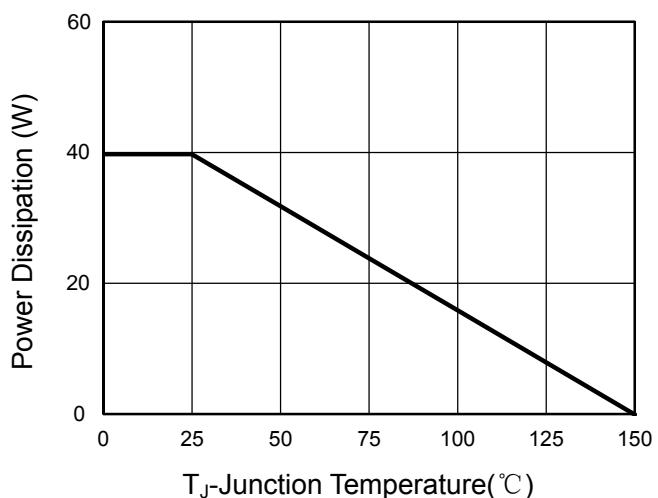
**Figure 3 Rdson- Drain Current**



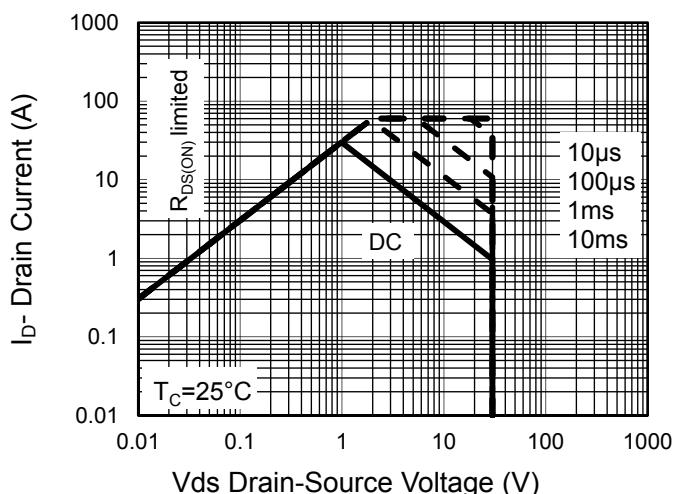
**Figure 6 Source- Drain Diode Forward**



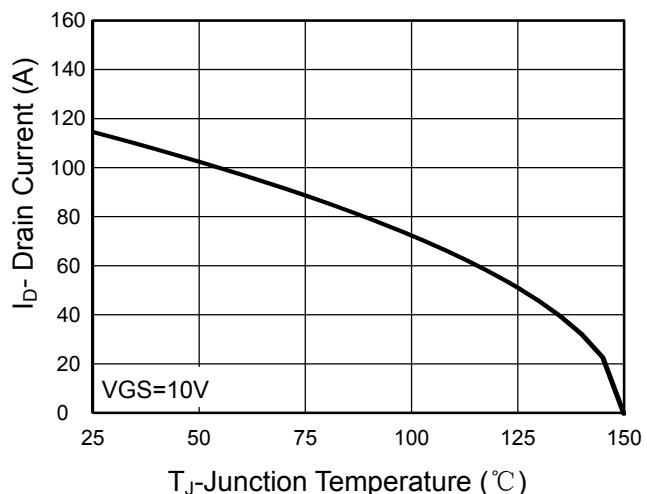
**Figure 7 Capacitance vs Vds**



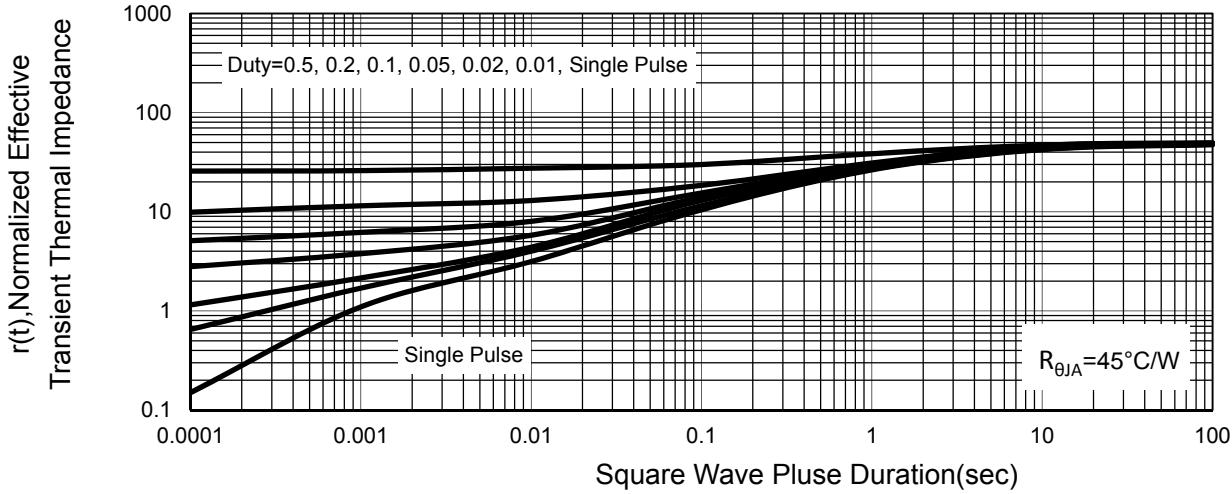
**Figure 9 Power De-rating**



**Figure 8 Safe Operation Area**



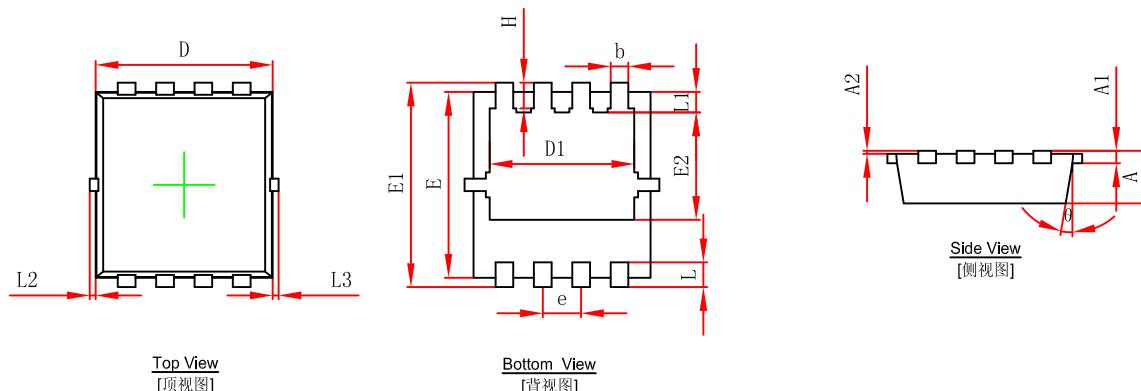
**Figure 10 Current De-rating**



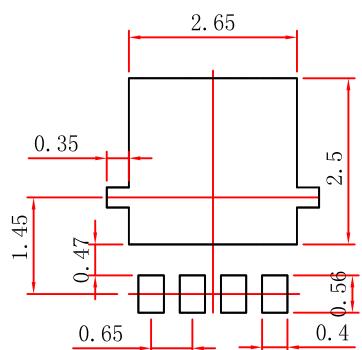
**Figure 11 Normalized Maximum Transient Thermal Impedance**



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**N - CHANNEL ENHANCEMENT MODE POWER MOSFET****SGT MOS、低内阻、低结电容开关损耗小****TF015N03MG****PDFNWB3.3x3.3-8L Package Outline Dimensions**

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.		0.006 REF.	
A2	0~0.05		0~0.002	
D	2.900	3.100	0.114	0.122
D1	2.300	2.600	0.091	0.102
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100		0~0.004	
L3	0~0.100		0~0.004	
H	0.315	0.515	0.012	0.020
θ	9°		9°	

**PDFNWB3.3x3.3-8L Suggested Pad Layout****Note:**

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.05\text{mm}$ .
3. The pad layout is for reference purposes only.